

NewTek™ Probe Needles

NewTek™ is available only from Advanced Probing Systems

NewTek™ is Advanced Probing Systems, Inc.'s proprietary, non-oxidizing probe needle material. The properties of NTK allow it to maintain low and stable contact resistance during wafer testing with minimal cleaning even at high temperatures. **NewTek** probe needles have been successfully used in low-K testing, to test pads with thin aluminum over copper, in test situations where multiple touchdowns are required as well as numerous other test applications. **NewTek** probe needles may be the optimal choice in situations where minimal pad damage is essential.

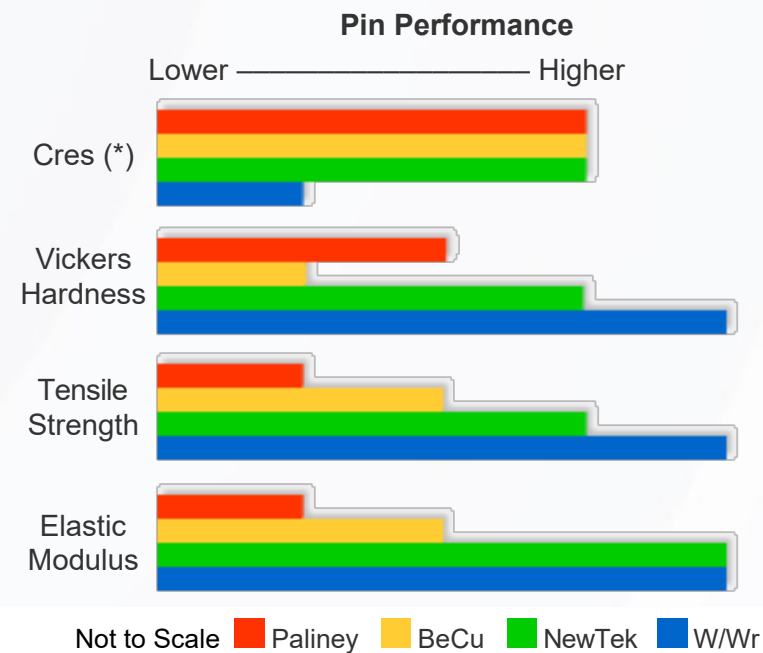
NewTek probe needles are available in standard pin diameters and lengths used in as well as in the nanotechnology diameters. NewTek is a very cost-effective alternative to current Palladium based alloys delivering similar performance.

NewTek™ Probe Needles is available in .003-.020 diameter pins.

Probe Needle Information References:

- [NewTek™ Press Release Download](#) (~360k)
- "Maximizing the Performance of An Atypical Cantilever Probe Wire Material" – Presentation by Frederick Taber to the 2006 Southwest Test Workshop" should also be included on this page. [Download](#) a pdf of this Powerpoint presentation (~360k)
- "Low and Stable Contact Resistance with Reduced Cleaning, a Paradigm Shift" – Presented by Jerry Broz and Rey Rincon at the 1999. www.swtest.org (opens in new window)
- "Understanding Probe-Contact a-Spot Oxidation During Elevated- Temperature Wafer Test" by Jerry Broz and Rey Rincon – Evaluation Engineering September 1999 ([Copies are available upon request from APS](#)).
- "Probe Contact Resistance Variations during Elevated Temperature Wafer Test" by Jerry Broz and Rey Rincon – presented at the 1999 International Test Conference. Copies are available at www.ieee.org (Membership and a small fee are required to access article).

NewTek™ as a Probe Material



Maximizing the performance of cantilever probe wire material

NewTek™ Probe Needles Wafer Sort

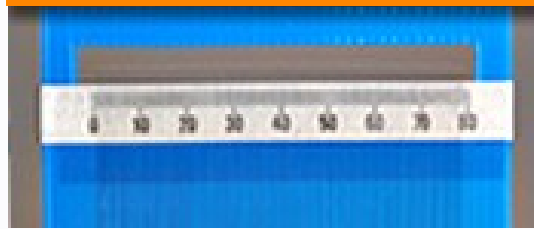
- low and stable contact resistance
- non-oxidizing pin
- minimal pad damage
- high temperature test
- cantilever test applications

Palladium Alloy & Beryllium-Copper



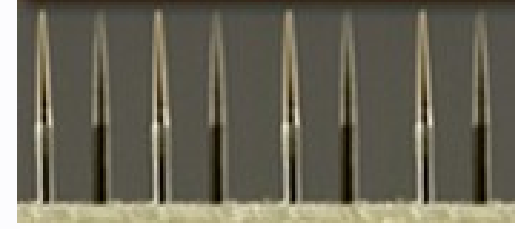
Pins in these materials are provided in diameters from .003" - .020" and are suitable for a variety of test and industrial applications.

Wafer Sort and Testing



Advanced Probing Systems manufactures probes suitable for cantilever wafer test.

Solid Pins in .020" Diameters or Larger



APS's capabilities to produce pins in diameters of .020" or larger for a variety of test and industrial applications.

